



Advances in Optical Instrument and Measurement Technology

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Message from the Guest Editors

Dear Colleagues,

In recent years, with the development of laser sources, measurement approaches and new materials, many new technologies or applications of measurement and new optical instruments have appeared. Therefore, this Special Issue is intended for the presentation of new ideas and experimental results in the field of high-performance optical instruments and measurement technology. Potential topics include, but are not limited to: optical design, fabrication and testing; ultrafast optic development; computational optical imaging; analog image processing with optical metasurfaces and metamaterials; novel techniques in microscopy; fiber-optic sensors; laser measurement; digital holographic metrology and sensing; micro- and nanophotoelectric measurement.

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Message from the Editor-in-Chief

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